Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and PressFit pin type. Intergrated with NTC temperature sensor.





2. Features and benefits

- · Half bridge topology
- PressFit pins technology
- Low R_{DSon}
- Low Switching Losses
- Low Q_g and C_{rss}
- Low Inductive Design

3. Applications

- Power inverters
- AC-DC converters
- DC-DC converters
- · Active power factor correctors
- Motor drivers

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes		Values		Unit	
Absolute maximum rating								
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V	
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			45		Α	
P _{tot}	total power dissipation	T _h = 25 °C			105		W	
Tj	junction temperature				-40 to 15	50	°C	
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit	
Static cha	aracteristics							
D3(0II)	drain-source on-state	$V_{GS} = 15 \text{ V}; I_D = 40 \text{ A}; T_j = 25 \text{ °C}$		-	40	-	mΩ	
resistance		V _{GS} = 18 V; I _D = 40 A; T _j = 25 °C		-	31.8	-	mΩ	
Dynamic	characteristics				•			
Q _{G(tot)}	total gate charge	$I_D = 40 \text{ A}$; $V_{DS} = 800 \text{ V}$; $V_{GS} = -4 \text{ V}/18 \text{ V}$;		-	125	-	nC	
Q_{GD}	gate-drain charge	T _j = 25 °C		-	19	-	nC	
Source-d	rain diode				'			
Q _r	recovered charge	I_{SD} = 40 A; V_{GS} = -4 V; di/dt = 8500 A/ μ s; V_{R} = 600 V; T_{j} = 25 °C		-	530	-	nC	

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WMSC040H12B1P	WeEnPACK-B1	WMSC040H12B1P6T	Tray	16	WeEnPACK- B1PHB-A	14-Dec-2023

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC040H12B1P	WMSC040H12B1P

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
T_{stg}	storage temperature			-40 to 150	°C
$T_{j.op}$	operating junction temperature			-40 to 150	°C
V _{ISOL}	RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
MOSFET					
V _{DS}	drain-source voltage	T _j = 25 °C		1200	V
$V_{\rm GS,max}$	gate-source voltage	Absolute maximum values		-12 to 24	V
$V_{\rm GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _h = 25 °C		105	W
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		45	Α
		V _{GS} = 18 V; T _h = 100 °C		28	Α
I _{DM}	peak drain current	pulse width t_p limited by T_{jmax}	Fig.17	90	Α
E _{as}	single pulse drain-to- source avalanche	I_{AS} = 15 A; L = 1 mH; V_{DD} = 100 V; $T_{j(init)}$ = 25 °C; per MOSFET		112.5	mJ
Body Diod	e				
I _{SD}	DC body diode forward current	V _{GS} = -4 V; T _h = 25 °C		24	А
I _{SD,pulse}	Pulse body diode current	verified by design, $t_{\scriptscriptstyle p}$ limited by $T_{\scriptscriptstyle jmax}$		90	Α

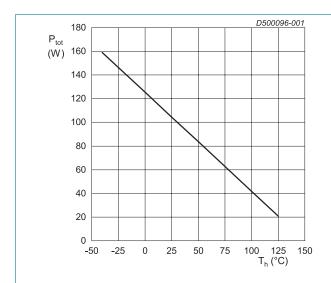


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

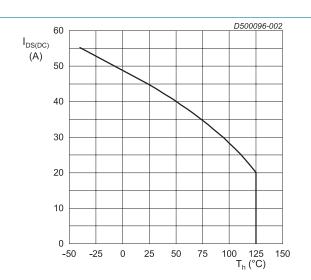


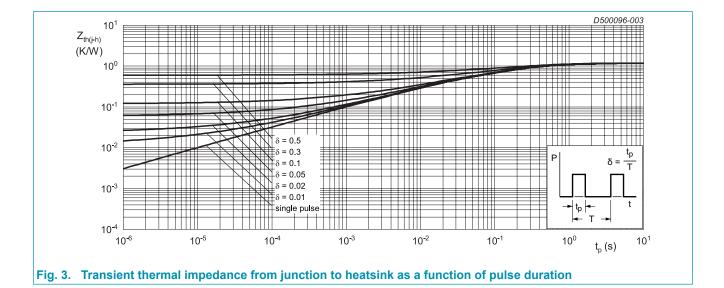
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	thermal resistance from junction to case	per MOSFET		-	0.51	-	K/W
R _{th(j-h)}	thermal resistance from junction to heatsink	per MOSFET, λ _{grease} = 1 W/(m·K)		-	1.20	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)			Al2O3		
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
СТІ	Comperative tracking index				>200		
F	Mounting force per clamp			20	-	50	N
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommanded.

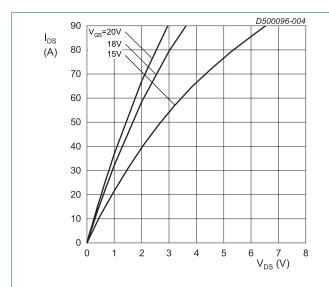


10. Characteristics

Table 7. Characteristics

MOSFET							
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		_		_		
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 200 \mu A; V_{GS} = 0 V; T_j = 25 °C$		1200	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 10 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C}$		1.9	2.5	3.5	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	0.4	200	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	20	200	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	20	200	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 40 A; T _j = 25 °C		-	40	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 40 A; T _j = 25 °C		-	31.8	-	mΩ
		V _{GS} = 18 V; I _D = 40 A; T _j = 125 °C		-	46.6	-	mΩ
		V _{GS} = 18 V; I _D = 40 A; T _j = 150 °C		-	52	-	mΩ
R_{G}	gate resistance, each side	f = 1 MHz; T_j = 25 °C, each die with 4.7 Ω $R_{G(ext)}$ in series		-	3.7	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 40 A; T _j = 25 °C		-	23	-	S
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 40 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	125	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	51	-	nC
Q_{GD}	gate-drain charge			-	19	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 1 MHz;		-	2.7	-	nF
C _{oss}	output capacitance	T _j = 25 °C		-	150	-	pF
C _{rss}	reverse transfer capacitance			-	12.9	-	pF
E _{oss}	Coss stored energy			-	75	-	μJ
t _{d(on)}	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	12	-	ns
t _r	rise time	$R_{G(ext)} = 2.4 \Omega$; $I_D = 40 A$; $L = 100 \mu H$; $T_i = 25 °C$		-	8	-	ns
$t_{\text{d(off)}}$	turn-off delay time	1		-	38	-	ns
t _f	fall time			-	17	-	ns
E _{on}	turn-on energy			-	490	-	μJ
E _{off}	turn-off energy			-	310	-	μJ

Body dio	de						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		,				
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V}; I_{SD} = 40 \text{ A}; T_j = 25 \text{ °C}$		-	5.6	-	V
		V_{GS} = -4 V; I_{SD} = 40 A; T_{j} = 150 °C		-	5.1	-	V
Dynamic	characteristics					'	
t _{rr}	reverse recovery time	I_{SD} = 40 A; V_{GS} = -4 V; di/dt = 8500 A/ μ s; V_{R} = 600 V; T_{j} = 25 °C		-	15	-	ns
Q _r	recovered charge			-	530	-	nC
I _{rrm}	reverse recovery current			-	56	-	Α
E _{rec}	reverse recovery energy			-	292	-	μJ
t _{rr}	reverse recovery time	I_{SD} = 40 A; V_{GS} = -4 V; di/dt = 10500 A/µs;		-	18	-	ns
Q_r	recovered charge	V _R = 600 V; T _j = 150 °C		-	1000	-	nC
I _{rrm}	reverse recovery current			-	85	-	Α
E _{rec}	reverse recovery energy			-	625	-	μJ
NTC ther	mistor		J				
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C		465±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	S



T_j = -40 °C; t_p < 200 μs Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

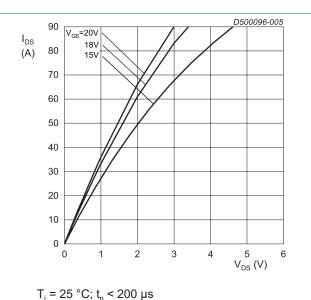
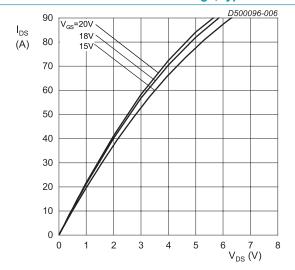
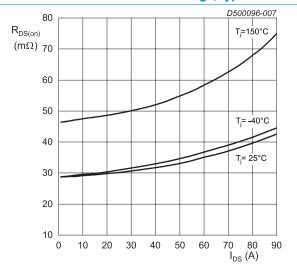


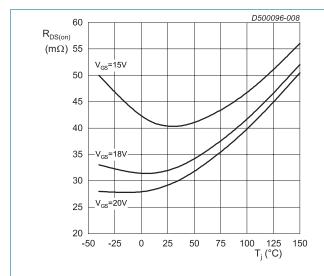
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



T_j = 150 °C; t_p < 200 μs Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

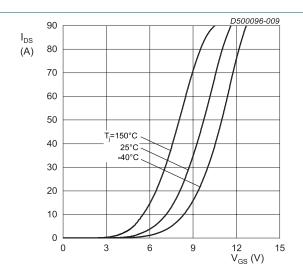


 V_{GS} = 18 V; t_p < 200 µs Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



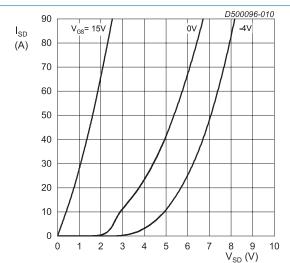
 $I_{DS} = 40 \text{ A}; t_p < 200 \text{ } \mu\text{s}$

Fig. 8. Drain-source on-state resistance as a function of junction temperature



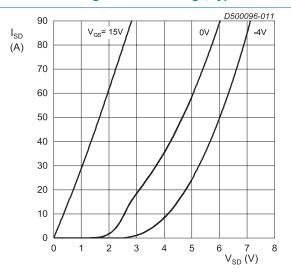
 V_{DS} = 20 V; t_{p} < 200 μs

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



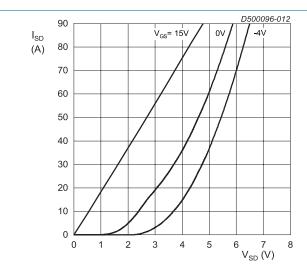
 $T_j = -40 \, ^{\circ}\text{C}; \, t_p < 200 \, \mu\text{s}$

Fig. 10. Body diode forward characteristics; typical values



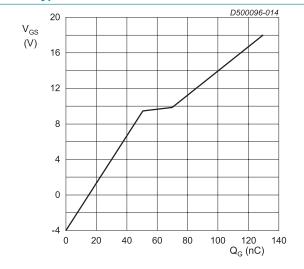
 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

Fig. 11. Body diode forward characteristics; typical values

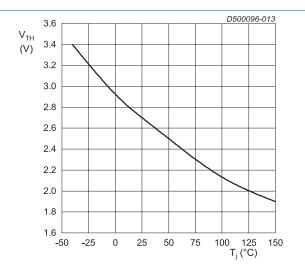


 T_j = 150 °C; t_p < 200 µs

Fig. 12. Body diode forward characteristics; typical values



 I_{DS} = 40 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values



V_{DS} = 10 V; I_{DS} = 10 mA Fig. 13. Threshold voltage as a function of junction temperature

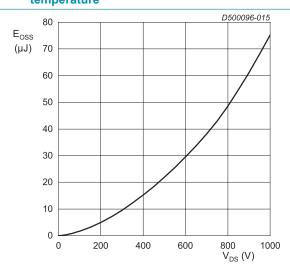
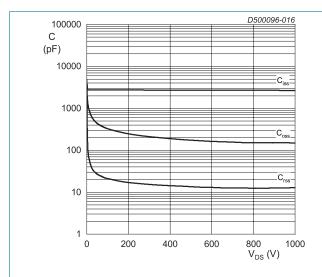
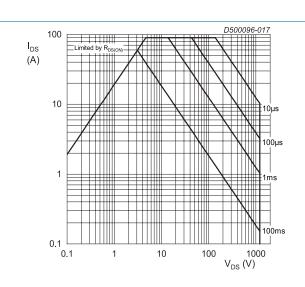


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



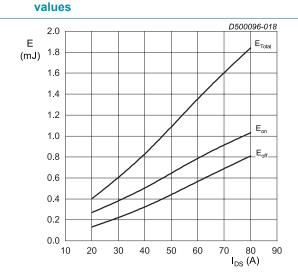
 $V_{DS} = 0 - 1000 \text{ V}$ $T_i = 25 \text{ °C; } V_{AC} = 25 \text{ mV; } f = 1 \text{ MHz}$

Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical



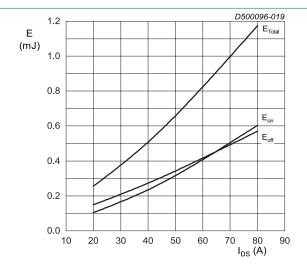
 $T_j = 25$ °C; D = 0 Parameter: t_p

Fig. 17. Forward bias safe operating area



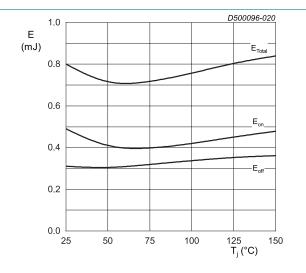
 $T_{j}=25~^{\circ}C;~V_{DD}=800~V;~R_{G(ext)}=2.4~\Omega;~R_{G(on)}=2.4~\Omega;\\ V_{GS}=-4~V/18~V;~L=100~\mu H$ Fig. 18. Clamped Inductive Switching Energy as a

function of drain current



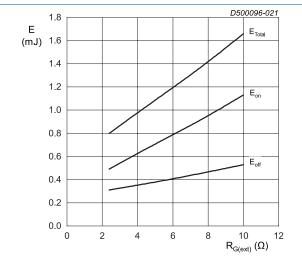
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 2.4 $\Omega;$ $R_{G(on)}$ = 2.4 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



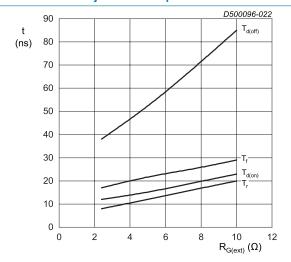
 I_{DS} = 40 A; V_{DD} = 800 V; $R_{G(off)}$ = 2.4 $\Omega;$ $R_{G(on)}$ = 2.4 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 40 A; $V_{\rm GS}$ = -4 V/18 V; L = 100 μH

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 40 A; $V_{\rm GS}$ = -4 V/18 V; L = 100 μH

Fig. 22. Switching time as a function of external gate resistance

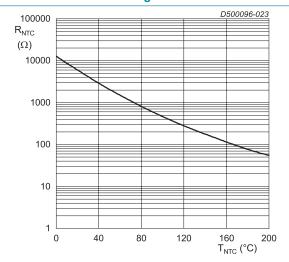
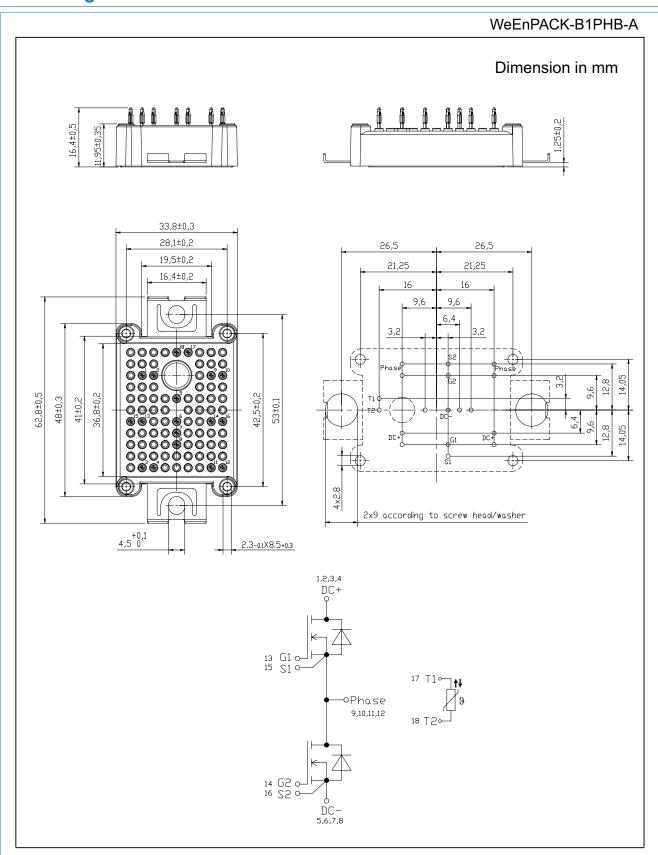


Fig. 23. NTC thermistor resistance as a function of NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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